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PO11 0PN (GB). JOLLY, Paul Harvey Ronald [GB/GB];
5 Lakeside, Funtley, Fareham Hampshire PO17 5EP (GB).

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(74) Agent: BEBBINGTON, Nicholas; Fulwood House, 12
Fulwood Place, London London WC1V 6HR (GB).

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(71) Applicant (for all designated States except US): XYRA-
TEX TECHNOLOGY LIMITED [GB/GB]; Langstone
Road, Havant Hampshire PO9 1SA (GB).

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(72) Inventors; and

(75) Inventors/Applicants (for US only): BRADY, Keith
Rowland Charles [GB/GB]; 150 Gordon Road, Fareham
Hampshire PO16 7TA (GB). QUICK, Gregory Martin
[GB/GB]; 27 Rogers Mead, Hayling Island Hampshire

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(54) Title: APPARATUS AND METHODS OF GENERATING A TEST PATTERN OF DATA, ANALYSING A TEST PATTERN OF DATA, AND TESTING A DATA STORAGE DISK MEDIUM AND/OR A READ/WRITE HEAD

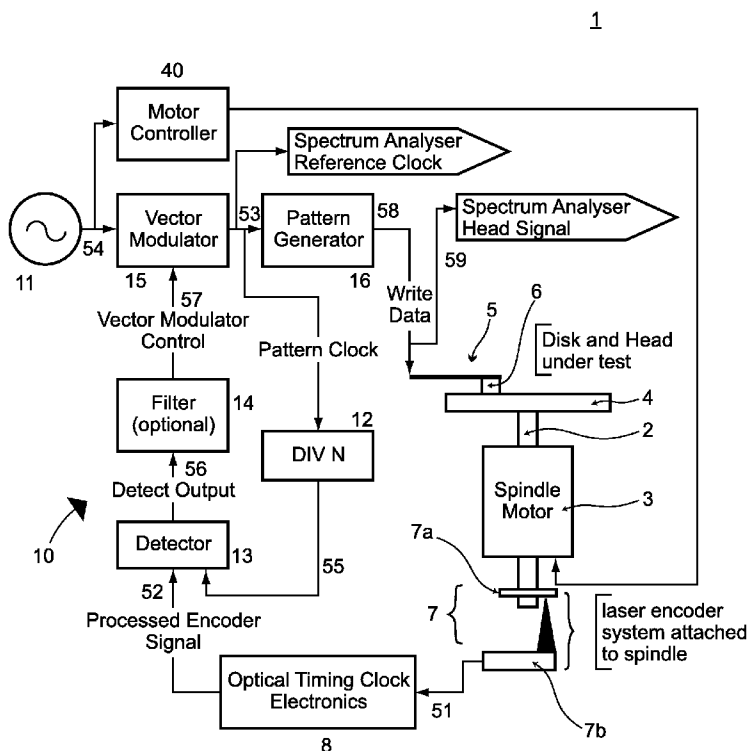


Fig. 1

(57) Abstract: There is disclosed apparatus and methods of generating a test pattern of data, analysing a test pattern of data, and testing a data storage disk medium and/or a read/write head. In a preferred embodiment there is disclosed a method of generating a test pattern of data to be written to a data storage disk medium (4) for testing. The method comprises: rotating the disk (4); detecting fluctuations in the speed of rotation of the disk (4); producing a reference clock signal (53) in accordance with said fluctuations so as to be synchronised with the rotation of the disk (4); and, generating a test pattern of data (58) using said reference clock signal (53) as a timing reference.



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